ITC 1998 Paper Awards

To encourage excellence in its technical program, ITC presents awards to authors of outstanding papers presented at ITC and published in the Proceedings. In determining award-winning papers, the ITC Awards Selection Committee considers the quality of the papers as published in the Proceedings and as presented at the conference technical sessions. The committee’s decisions are based on responses by conference attendees as recorded on session rating cards and on the observations and recommendations of the ITC Program Committee.

For 1998, the Awards Selection Committee has selected as Best Paper Award winner the paper “Failure Analysis of Timing and I_{DDQ} only Failures from the SEMATECH Test Methods Experiment” by Phil Nigh, Dave Vallett, Atul Patel and Jason Wright, all with IBM Microelectronics and Franco Motika, Donato Forlenza, Ray Kurtulik and Wendy Chong with Micrus Corporation. The authors conducted diagnosis and failure analysis on a number of devices that had timing failures or I_{DDQ} failures, and identified the impact the underlying defects had on normal operation of the device.

The Awards Selection Committee also selected two papers of outstanding merit for Honorable Mention Awards. “Defect Detection with Transient Current Testing and its Potential for Deep Sub-micron CMOS ICs” by Manoj Sachdev, Peter Janssen and Victor Zieren with Philips Research Laboratories demonstrates the practicality of using transient IDD measurements. “Probabilistic Mixed-Model Fault Diagnosis” by David Lavo, Brian Chess and Tracy Larrabee with University of California Santa Cruz and Ismed Hartanto with Hewlett-Packard Company shows how a combination of fault models can be used to enhance IC diagnosis.

The International Test Conference congratulates the authors of these papers for their achievements and for the outstanding quality of their work. The $2000 Best Paper Award and $1000 Honorable Mention Award and commemorative plaques will be presented to the authors during the 1999 International Test Conference.